C63® American National Standards Committee C63®

Electromagnetic Compatibility

Subcommittee 5: Immunity Testing and Measurements

Chair: Tom Braxton **Vice Chair:** Dave Schaefer **Secretary:** Jerry Ramie

May 6, 2026; 10:15 AM – 12:00 PM - MDT
NIST, Boulder, CO - Web-meeting

Approved Minutes

1. Call to Order: Chair - The Chair called the meeting to order at 10:20 AM-MDT.

1.1 Announcements: Chair's remarks - Thanks for attending! The Vice Chair is running the meeting today.

1.2 Meeting logistics announcements: Host - restrooms on the left through the doors

1.3 Introductions: Secretary – roll call (record attending members with their affiliations and guests separately below) (SC5 membership roster from the website is shown below) Absences, excused absences and errors are shown below;

Subcommittee 5 Membership Roster **Report any roster errors to the ASC-C63® Secretary**

Name	Role within SC	Affiliation
Braxton, Tom	Chair	ARRL (Expert)
DeLisi, Bob	Member	UL LLC / Primary
Fanning, Craig	Member	Elite Electronic Engineering (Primary Rep)
Griffin, Andy	Member	Cisco Systems / Primary
Hoolihan, Dan	Member	Hoolihan EMC Consulting
Long, Randy	Member	ANSI National Accreditation Board / Primary
Ramie, Jerry	Secretary/Member	Consultant (ARRL Technical Expert)
Schaefer, Dave	Vice Chair	Element Materials Technology (Alternate Rep)
Silberberg, Jeffrey L	Member	Member Emeritus
Zimmerman, Dave	Member	Spectrum EMC, LLC

Guests and Observers: (non-voting) Henry Benitez, William Elliott, Bill Koerner, Cathy Miller, Ken Gjerde, Megan McConnell, Bob Mitchell, Steve Koster, Doug Kramer, Victor Kuczynski

1.4 Quorum: (50% of roster) constitutes a quorum. (rounding up) (10 roster members / 2 = 5 >> (therefore **5 people are required** for a quorum) **Was quorum achieved? (Yes)** If not, any actions taken are subject to confirmation by electronic ballot or at a future meeting. Roster above was modified and re-posted 5/19/2026.

2. Approval of the Consent Agenda (includes Agenda & Previous Minutes): Secretary - no objections, the Consent Agenda was accepted by acclamation. (**Approved Previous Minutes**)

2.1 Review of the patent slides - The slides were shown and all agreed to the pollicies.

3. Review of Subcommittee Membership: Secretary - Report any errors in Item 1.3 above to the ASC-C63® Secretary

3.1 Review of Membership Guidelines – any members at risk?

Subcommittees:
For an individual to remain a voting member of a Subcommittee, active participation in Subcommittee meetings and regular responses to Subcommittee email votes is required. Should a member fail to attend at least one of three consecutive scheduled meetings (in person or remotely via web conference (when used)) or respond to at least one of every two consecutive Subcommittee email votes, their membership in that Subcommittee may be at risk.

Note: Abstentions shall be treated the same as a "yes" or "no" vote regarding the requirement to respond to email votes.

Working Groups:
For an individual to remain a member of a Working Group, active participation is required. Should a member fail to attend at least one of three consecutive scheduled meetings (in person or via web conference (when used)) their membership in that Working Group may be at risk. Individual Working Groups may establish additional participation criteria and/or modify this requirement.

Member Attendance Log:

20220518	20221109	20230119	20230316	20230511	20231004	20240516	20241002	20250505	20251006	SC5 Members
			x	x	x	x	x	x	x	Tom Braxton
x	x	x	x	x	x	x	x	x	x	Bob DeLisi
x	x	x	x		x	x	x	x	x	Craig Fanning
x		x	x		x		x	x		Andy Griffin
x	x			x	x	x	x			Dan Hoolihan
x	x	x	x	x	x	x	x	x		Randy Long
x	x	x	x	x	x	x	x	x	x	Jerry Ramie
x	x				x	x		x		David Schaefer
x	x	x	x	x	x	x	x	x		Jeff Silberberg
		x		x	x		x	x	x	Dave Zimmerman

Members at risk? **None** are at risk:

3.2 Consideration of new members? Application for C63® Subcommittee Membership - none

3.3 Approval of Membership (Spring meeting only)

4. Approval of Scope, Duties and Roster: Chair - (Spring meeting only) (Report approval or any changes to the Main Committee)

4.1 Scope - *Subcommittee 5 is responsible for developing and maintaining new and existing ANSC C63® standards for immunity testing techniques and associated instrumentation as requested by the Main Committee ANSC C63®.*

Duties - *C63.9; C63.15, C63.16, C63.24*
Roster - see above

Jerry moved, seconded by Dan H. to approve the Scope, Duties & Roster. No opposition. **The Scope, Duties and Rosters (as amended) were accepted.**

4.2 ~~Election of Officers~~ (as required) Officer's terms end 12/31/2026 AI-131: Bob D. to inquire with Tom B. if he is willing to serve another term

5. Working Group reports - Chair - More information about each standard is available on the Standards Status Matrix page of the C63® web site. This information will be reviewed for accuracy at each Spring Subcommittee meeting. WG reports shall be made using the C63_PowerPoint_template_wide.

5.1 C63.9 – Office Equipment Immunity - None (no WG report)

5.1.1 Status Matrix Review: Verify accuracy of document status matrix content and report any errors to the ANSC-C63® Secretary. **Is this information correct? (Yes)** (repeat this verification for all Standards covered by this Subcommittee)

C63.9-2024 Learn more	Laboratory immunity testing of office equipment exposed to RF sources	SC 5	None	C63.9 PINS	Published 5/12/25.

C63.9: C63.9-2024 American National Standard for laboratory Immunity testing of Office Equipment exposed to RF sources
Contact: Braxton, Tom
Scope: This standard provides recommended test methods and limits for assuring the RF immunity of multimedia equipment to a wide variety of common and ubiquitous RF sources from mobile phones to licensed transmitters.
Status: published 5/12/25
Purchase: Search IEEE Standards - Enter C63 Standard number then Search (Enter) - Click on the version you want - Click on Purchase

5.2 C63.15 – Immunity Measurement & Instrumentation - None (no WG report)

5.2.1 Status Matrix Review: Verify accuracy of document status matrix content and report any errors to the ANSC-C63® Secretary. **Is this information correct? (Yes)**
AI-120: Bob will ask Jennifer about the sales of this Standard. The consensus was to re-affirm the document while we open it to see if it needs work. Bob reports 405 PDF and 14 paper versions were sold.

AI-121: Tom formed a small Task Group to generate a C63.15 re-affirmation PINS and list of possible changes. (Tom, Jerry, Richard, Andy) Jerry found the previous version in SC5 records. Comment period on C63.15 re-affirmation PINS ended 12/5/2025, no vote taken; awaiting response from Tom B.

C63.15-2017 Learn more	Immunity Measurement & Instrumentation	SC 5	None	No active PINS	Published 2017 Working group disbanded

C63.15: C63.15-2017 American National Standard Recommended Practice for the Immunity Measurement of Electrical and Electronic Equipment
Contact: None (Working Group Chair)
Scope: This immunity measurement and measurement instrumentation recommended practice document complements the emission measurement procedures specified in ANSI C63.4 noting that C63.15 is a recommendation while C63.4 is a standard. The immunity methods are of use to manufacturers who want to produce a reliable product working in the customer location RF environment to reduce customer complaints. This document generally covers the frequency range of 30 Hz to 10 GHz. The test instrumentation needed to replicate the RF environment is also identified that will support the immunity testing.
Status: Published in 2017. Working group disbanded.
Purchase: Search IEEE Standards - Enter C63 Standard number then Search (Enter) - Click on the version you want - Click on Purchase

5.3 C63.16 – ESD Test Methodology - Braxton (no WG report)

5.3.1 Status Matrix Review: Verify accuracy of document status matrix content and report any errors to the ANSC-C63® Secretary. **Is this information correct? (Yes)** BSR published 9/5/25. Tracked Changes version of the ballot document was sent 3/9/2026.

C63.16-2025 Learn more	ESD Test Methodology	SC 5	None	C63.16 PINS	BSR9 in progress.

C63.16: C63.16-2016 American National Standard Guide for Electrostatic Discharge Test Methodologies and Criteria for Electronic Equipment
Contact: None (Working Group Chair)
Scope: This guide provides electrostatic discharge (ESD) test considerations that a manufacturer should use in assessing the expected ESD effects on products in a wide range of environments and customer use. The focus is well beyond that used to simply show that a product complies with a local, regional, or international standard or regulation. The guide includes unique new material on testing of charged peripherals being connected to a system and system components being placed in a docking station. It also includes information on the use of preliminary investigatory testing to identify test points, methods for visually documenting the location of those test points, and the use of a stepped approach in ratcheting up the test voltage to determine

failure thresholds. The annexes include test plan and data sheet examples along with more background on air and contact discharge for those who want to further understand the differences in these methods.
Status: BSR9 in progress.
Purchase: Not available for purchase

5.4 C63.24 – In-Situ RF Immunity Evaluation of Electronic Devices and Systems - Schaefer (no WG report) The C63.24 roster was re-populated with former members. C63.24_PINS-C generated and reviewed by JLS on 1/30/2026. Any edits to C63.24_PINS-C? The Subcommittee reviewed the amended PINS-C and Jerry moved to accept it, seconded by Jeff S. SC5 has accepted by acclamation this modified C63.24_PINS-C. Dave will include this file in the SC5 report to the Main.

5.4.1 Status Matrix Review: Verify accuracy of document status matrix content and report any errors to the ANSC-C63® Secretary. **Is this information correct? (No)**

C63.24-2021 Learn more	In-Situ RF Immunity Evaluation of Electronic Devices and Systems	SC 5	Schaefer, Dave	C63.24_PINS-C	Published 3/31/2021. Working group disbanded. A C63.24_PINS-C was approved by SC5 on 5/6/2026

C63.24-draft: American National Standard Recommended Practice for In-Situ RF Immunity Evaluation of Electronic Devices and Systems
Contact: Schaefer, Dave (Working Group Chair)
Scope: This recommended practice provides an in-situ EMC immunity qualification test for products, instrumentation, and control systems in their installed environment. The recommended practice will focus on installation environments that require a high level of confidence that these products and systems have a high level of EMC immunity. This project will provide a generic method for evaluating the RF immunity of electronic products, instrumentation, and control systems, as and where installed or operated. A particular focus is on immunity to RF sources that may enter the environment, intentionally or unintentionally or be integrated into the operating environment. The characteristics of RF sources in the environment will be used to establish the levels and test methods.
Status: Published 3/31/2021 Working group disbanded. A C63.24_PINS-C was approved by SC5 on 5/6/2026
Purchase: Search IEEE Standards - Enter C63 Standard number then Search (Enter) - Click on the version you want - Click on Purchase
AI-132: Jerry to modify the C63.24 listing on the status matrix as above (posted 5/19/2026)

6. Other Old Business: Chair

6.1 Written reports - Written reports of this Subcommittee meeting shall be presented by the Subcommittee Chair at the Main Committee meeting. These reports shall be made using the C63_PowerPoint_template_wide. Prior to the Main Committee meeting, the SC report and approved previous SC meeting minutes shall be provided to the projectionist for showing on the screen at the Main meeting. The Presentation and any written report shall also be sent by the Subcommittee Chair to the ANSC-C63® Newsletter editor.

6.2 Coordination with SC2 for definitions - Before any Working Group draft can be submitted to a Subcommittee for approval, the document must be provided to the SC2 Chair for evaluation and coordination of the definitions used.

6.3 Coordination with SC3 for harmonization - Only a Subcommittee can submit a Working Group draft for evaluation and coordination of any harmonization effort.

7. New Business: Chair

7.1 Review of C63.15 Tom formed a small Task Group to generate a C63.15 re-affirmation PINS and list of possible changes. (Tom, Jerry, Richard, Andy) Jerry found the previous version in SC5 records. Comment period on C63.15 re-affirmation PINS ended 12/5/2025, sent to SC5 on 11/13/2026. No responses; awaiting response from Tom Braxton if a new vote should be taken. Any edits to the C63.15 re-affirmation PINS? Jerry moved, seconded by Dan H. to accept the reaffirmation PINS and advance it to the Main Committee for approval. No discussion. No objections. The motion carried. **The C63.15 re-affirmation PINS was approved for advancement to the Main.**

7.2 Review C63.16. BSR published 9/5/25.

7.3 Immunity testing of lighting products? - Mendoza - do lighting products require immunity tests? (not discussed at the last meeting)

7.4 Where is SC5 going? - Braxton - This was discussed at the last meeting. Tom showed a presentation on immunity needs in other industries. See AI-117: Tom produced a draft letter and list of trade associations for mailing re/ immunity testing. AI-128: Tom narrowed the scope of the new letter to other industries and can bring it to the Steering Committee.

Previous Discussion: Consider offering a Presentation at their meetings. We could offer new documents if they require them. Victor suggested using "No fault found" reports as guidance for where to look for problems.

7.5 C63.24 being re-opened? - Schaefer - The **C63.24 (In Situ Immunity Testing) Working Group Roster** was restored from 11/18/2019:

C63.24 (In Situ Immunity Testing – Generic) Working Group Roster

Name	Role in WG	Affiliation
Schaefer, Dave	Chair	Element Materials Technology
Ramie, Jerry	Secretary	Consultant
Fanning, Craig	Member	Elite Electronic Engineering
Harrington, Tim	Member	FCC
Kiger, Chad	Member	AMS Corporation
Silberberg, Jeffrey L	Member	Member Emeritus
Walton, Derek	Member	LF Research
IEEE-473 Liaison Members		
Name	**Role in WG**	**Affiliation**
Benitez, Henry	Member	Electromagnetic Investigations
Duffy, Alistair	Member	De Montfort University
Dyberg, Karen	Member	Raytheon
Hiltz, Greg	Member	Dept. of National Defense, Canada
McRae, Kingsley	Member	EMC Society Australia
Sze, Kin	Member	Dept. of National Defense, Canada
Williams, Kimball	Member	IEEE - EMC Society

The C63.24 roster was re-populated with former members. A C63.24_PINS-C was generated and reviewed by JLS on 1/30/2026. SC5 considered this file and produced this modified C63.24_PINS-C. **Dave S. will include this modified C63.24_PINS-C in the SC5 report to the Main.**

7.6 Resilience testing - Braxton - IEC dictionary definition of Resilience:

Resilience: *the ability of an item to return to functional capability, within an acceptable time period, after having been affected by inputs or conditions when subjected to circumstances that are outside those specified or intended*

Previous Discussion: Resilience could be viewed as another form of immunity, to be "resilient" to interference. (multiple phenomena, poor management, etc.) Immunity testing cannot predict if a product performs well in the field. A medical Std. IEC 60601-4-6, similar to IEC 61000-1-2, assumes you can't test for electromagnetic safety of a product. (similar to software with many variables) AI-130: Tom to contact Davy Pissort to obtain reports or white papers on "resilience."

8. C63.org website use and updates: Secretary - We normally post documents to the SC5 protected area. If any WG needs help with this posting, a ***Technical Secretary*** is available to assist.

9. Review of the Action Items: Secretary

9.1 Review of Action Items from this meeting: (read Action Items to Members, who must agree that they understand their meaning)

9.2 Review of Action Items from previous meeting: The consolidated Action Items table from the previous meeting Minutes is shown below:

Consolidated Action Items from 10/06/25 Meeting of SC5

Action Item #	Subject	Responsible Person(s)	Status	Delivery Date	Comments
AI-120:	Bob will ask Jennifer about the sales of this C63.15 Standard.	Bob DeLisi	Closed	Next meeting	consensus was to re-affirm the document while we open it to see if it needs work. Msg sent 10/6
AI-124:	Jerry to add Jeff S. to SC5 roster	Jerry Ramie	Closed	Next meeting	Added 10/15
AI-125:	Bob will ask Jennifer about the sales of the C63.15 Standard	Bob DeLisi	Closed	Next meeting	
AI-126:	Tom to form a small Task Group to generate a C63.15 re-affirmation PINS and list of possible changes. (Tom, Jerry, Richard W., Andy)	Tom Braxton Jerry Ramie	Closed	Next meeting	Jerry has found the previous version in SC5 records.
AI-127:	Jerry & Tom & Jeff S. & Bob D. will begin work on the C63.15 re-affirmation PINS on Nov. 13 @ 2:00PM-EST	Tom Braxton Jerry Ramie Jeff Silberberg Bob DeLisi	Closed	Next meeting	Meeting set 10/15
AI-128:	Tom to narrow the scope of the new letter to other industries and bring it to the Steering.	Tom Braxton	Closed	Next meeting	Not sent yet...
AI-129:	Jerry to set up a C63.24 web-meeting to discuss a C63.24_PINS-C generic in-situ immunity testing. (WPT, etc.) Dave, Tom, Craig, Conrad, Jerry, Jeff on Dec 2 @ 2:00PM-EST	Jerry Ramie	Closed	Next meeting	Meeting set 10/15
AI-130:	Tom to contact Davy Pissort to obtain reports or white papers on "resilience."	Tom Braxton	Open	Next meeting	

10. Time and place of next meeting: Chair - **Week of Oct. 19 @ A2LA (Frederick, MD)**

11. Closing remarks and Adjournment: Chair - The Chair thanked the attendees for their inputs and adjourned the meeting at 11:10AM-MDT.

********** End of Meeting **********

Consolidated Action Items from 05/06/26 Meeting of SC5

Action Item #	Subject	Responsible Person(s)	Status	Delivery Date	Comments
AI-130:	Tom to contact Davy Pissort to obtain reports or white papers on "resilience."	Tom Braxton	Open	Next meeting	
AI-131:	Bob D. to inquire with Tom B. if he is willing to serve another term	Bob DeLisi	Open	Next meeting	
AI-132:	Jerry to modify the C63.24 listing on the status matrix as above	Jerry Ramie	Closed	Next meeting	posted 5/19/2026